	Application No.	Applicant(s)
Notice of Allowability	09/486,561	HASHIMOTO, NOBUAKI
	Examiner	Art Unit
	David A. Zameke	2891
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication IGHTS. This application is subject to	plication. If not included  n will be mailed in due course. THIS
1.   This communication is responsive to the amendment filed.	<u>5/18/05</u> .	
2. X The allowed claim(s) is/are 8,11,12,14-16,21,22 and 24-26		
3. X The drawings filed on 29 May 2001 are accepted by the Ex	kaminer.	
4. ☑ Acknowledgment is made of a claim for foreign priority una) ☑ All b) ☐ Some* c) ☐ None of the:  1. ☑ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)).  * Certified copies not received:  Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.  5. ☐ A SUBSTITUTE OATH OR DECLARATION must be subminsFORMAL PATENT APPLICATION (PTO-152) which give 6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must (a) ☐ including changes required by the Notice of Draftspers 1) ☐ hereto or 2) ☐ to Paper No./Mail Date  (b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	e been received. e been received in Application No cuments have been received in this of this communication to file a reply lENT of this application.  itted. Note the attached EXAMINER es reason(s) why the oath or declara it be submitted. on's Patent Drawing Review ( PTO- es Amendment / Comment or in the Comment o	complying with the requirements  'S AMENDMENT or NOTICE OF tion is deficient.  948) attached  Office action of
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in the	.84(c)) should be written on the drawing the header according to 37 CFR 1.121(	ngs in the front (not the back) of d).
<ol> <li>DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT I</li> </ol>		
Attachment(s)  1. ☐ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 5/26/05  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☐ Examiner's Amendr	te
		David A. Zarneke Primary Examiner - AU2891 August 4, 2005

## **DETAILED ACTION**

## Examiner's Amendment

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows: Cancel claims 3, 4, 9, 10, 13, and 17-20 as nonelected claims.

## Reasons for Allowance

The following is an examiner's statement of reasons for allowance: Prior art could not be located that taught a conductive adhesive said adhesive having a first portion and a second portion, said first portion interposed between a surface of said substrate on which said interconnect pattern is formed and a surface of said semiconductor chip on which said electrodes are formed, said second portion overlapping with said semiconductor chip between said second portion of said adhesive covers all area of lateral surfaces of said semiconductor chip that is substantially perpendicular to the surface of the semiconductor chip on which the electrodes are formed, and a thickness of any part of said second portion of said adhesive is thicker than an interval between the surface of the semiconductor chip on which said electrodes are formed and said interconnect pattern on said substrate.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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## Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to David A. Zarneke whose telephone number is (571)-272-1937. The examiner can normally be reached on M-Th 7:30 AM-6 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, William Baumeister can be reached on (571)-272-1722. The fax phone number for the organization where this application is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

August 4, 2005